

<b>Notice of References Cited</b>	Application/Control No. 10/811,682		Applicant(s)/Patent Under Reexamination CHAN ET AL.	
	Examiner William J. Klimowicz		Art Unit 2627	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,489,356	12-1984	Farmer, Paul L.	360/97.02
*	B	US-6,728,062	04-2004	Ou-Yang et al.	360/97.02
*	C	US-6,788,493	09-2004	Subramaniam et al.	360/97.02
*	D	US-6,898,048	05-2005	Adams et al.	360/97.02
*	E	US-6,999,273	02-2006	Tsang et al.	360/97.02
*	F	US-7,057,851	06-2006	Sun et al.	360/97.02
*	G	US-7,123,439	10-2006	Chan et al.	360/97.02
*	H	US-2004/0252405	12-2004	Sun et al.	360/097.02
*	I	US-2005/0041329	02-2005	Chan et al.	360/097.02
*	J	US-2005/0041332	02-2005	Chan et al.	360/097.02
*	K	US-2006/0028760	02-2006	Zuo et al.	360/097.02
*	L	US-2006/0066992	03-2006	Chan et al.	360/097.03
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001023347 A	01-2001	Japan	HASHIZUME et al.	
	O	JP 2002109858 A	04-2002	Japan	IMAI et al.	
	P	JP 2002133827 A	05-2002	Japan	NAKAMOTO et al.	
	Q	JP 2002208270 A	07-2002	Japan	GARIKIPATI et al.	
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.